

Title (en)
CONTROLLED ATOMIC FORCE MICROSCOPE

Title (de)
GESTEUERTES ATOMKRAFTMIKROSKOP

Title (fr)
MICROSCOPE A FORCE ATOMIQUE ASSERVI

Publication
EP 2029998 A1 20090304 (FR)

Application
EP 07766092 A 20070523

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Abstract (en)
[origin: WO2007135345A1] The invention relates to an atomic force microscope comprising a microtip (1) placed on a flexible support connected to a microscope head (11) facing a surface (5) to be studied, which includes means (31, 32) for controlling the distance between said head and said surface for a given value and means (31, 35) for inhibiting vibration of the microtip.

IPC 8 full level
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Citation (search report)
See references of WO 2007135345A1

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